

INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT  
Form PTO-1449 (Modified)  
(Use several sheets if necessary)

COMPLETE IF KNOWN

Application Number	10798,753
Confirmation Number	
Filing Date	
First Named Inventor	Jack Zezhong Peng
Group Art Unit	2827
Examiner Name	

Sheet 1 of 4 Attorney Docket No. 384848014US

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	U.S. Patent or Application		Name of Patentee or Inventor of Cited Document	Date of Publication or Filing Date of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		NUMBER	Kind Code (if known)			
		3,634,929		Yoshida et al.	01/18/72	
		4,322,822		McPherson	03/30/82	
		4,488,262		Basire et al.	12/11/84	
		4,490,900		Chiu	01/01/85	
		4,502,208		McPherson	03/05/85	
		4,507,757		McElroy	03/26/85	
		4,543,594		Mohsen et al.	09/24/85	
		4,546,273		Osman	10/08/85	
		4,599,705		Holmberg, et al.	07/08/86	
		4,613,886		Chwang	09/23/86	
		4,677,742		Johnson	07/07/87	
		4,758,986		Kuo	07/19/88	
		4,794,562		Kato et al.	12/27/88	
		4,823,181		Mohsen et al.	04/18/89	
		4,876,220		Mohsen et al.	10/24/89	
		4,899,205		Hamdy et al.	02/06/90	
		4,943,538		Mohsen et al.	07/24/90	
		4,962,342		Mead et al.	10/09/90	
		5,138,410		Takebuchi	08/11/92	
		5,150,179		Gill	09/22/92	
		5,303,185		Hazani	04/12/94	
		5,304,871		Dharmarajan et al.	04/19/94	
		5,323,342		Wada et al.	06/21/94	
		5,412,244		Hamdy et al.	05/02/95	
		5,477,499		Van Buskirk et al.	12/19/95	
		5,496,756		Sharma et al.	03/05/96	
		5,576,568		Kowshik	11/19/96	
		5,578,848		Kwong et al.	11/26/96	

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				First Named Inventor	Jack Zezhong Peng
				Group Art Unit	2827
				Examiner Name	G. N. Auduong
Sheet	2	of	4	Attorney Docket No.	384848014US

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		NUMBER	Kind Code (if known)			
		5,586,270		Rotier et al.	12/17/96	
		5,587,603		Kowshik	12/24/96	
		5,600,265		El Gamal et al.	02/04/97	
		5,675,541		Leterrier	10/07/97	
		5,675,547		Koga	10/07/97	
		5,745,417		Kobayashi et al.	04/28/98	
		5,825,200		Kolze	10/20/98	
		5,825,201		Kolze	10/20/98	
		5,880,512		Gordon et al.	03/09/99	
		5,909,049		McCollum	06/01/99	
		5,986,931		Caywood	11/16/99	
		5,986,939		Yamada	11/16/99	
		6,016,268		Worley	01/18/00	
		6,034,893		Mehta	03/07/00	
		6,040,968		Duvvury et al.	03/21/00	
		6,064,595		Logie et al.	05/16/00	
		6,084,428		Kolze et al.	07/04/00	
		6,097,077		Gordon et al.	08/01/00	
		6,157,568		Schmidt	12/05/00	
		6,166,954		Chern	12/26/00	
		6,214,666		Mehta	04/10/01	
		6,215,140		Reisinger et al.	04/10/01	
		6,218,274		Komatsu	04/17/01	
		6,232,631		Schmidt et al.	05/15/01	
		6,249,809		Bro	06/19/01	
		6,282,123		Mehta	08/28/01	
		6,294,809		Logie	09/25/01	
		6,297,103		Ahn et al.	10/02/01	

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<i>G. N. Auduong</i>	<i>7/05</i>
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		NUMBER	Kind Code (if known)			
C		6,304,666		Warren et al.	10/16/01	
C		6,351,428		Forbes	02/26/02	
C		6,421,293		Candelier et al.	07/16/02	
C		6,431,456		Nishizawa et al.	08/13/02	
C		6,456,535		Forbes et al.	09/24/02	
C		6,556,481		Hsu et al.	04/29/03	
C		US2001/0003374		Bohmer et al.	06/14/01	

**FOREIGN PATENT DOCUMENTS**

Examiner Initials*	Cite No.	Foreign Patent or Application			Name of Patentee or Applicant of Cited Document	Date of Publication or Filing Date of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T
		Office	NUMBER	Kind Code (if known)				
C		EP	0 295 935	A1	Advanced Micro Devices, Inc.	12/21/88		
C		JP	61292295		Fujitsu Ltd.	12/23/86		

**OTHER PRIOR ART-NON PATENT LITERATURE DOCUMENTS**

Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume issue number(s), publisher, city and/or country where published.	T
C		MIRANDA, ENRIQUE et al; Analytic Modeling of Leakage Current Through Multiple Breakdown Paths in SiO <sub>2</sub> Films; 39 <sup>th</sup> Annual International Reliability Physics Symposium; Orlando, FL 2001.	
		LOMBARDO, S. et al; Softening of Breakdown in Ultra-Thin Gate Oxide nMOSFET's at Low Inversion Layer Density; 39 <sup>th</sup> Annual International Reliability Physics Symposium; Orlando, FL 2001.	
		WU, E.W. et al; Voltage-Dependent Voltage-Acceleration of Oxide Breakdown for Ultra-Thin Oxides; IEEE, 2000.	
C		RASRAS, MAHMOUD et al; Substrate Hole Current Origin After Oxide Breakdown; IEEE, 2000.	

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Sheet

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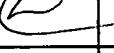
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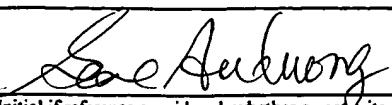
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		SUNE, JORDI et al; Post Soft Breakdown Conduction in SiO <sub>2</sub> Gate Oxides; IEEE, 2000.	
		DeGRAAF, C., et al, A Novel High-Density Low-Cost Diode Programmable Read Only Memory, IEEE, 1996.	

EXAMINER



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PTO/SB/08a/b (08-03)

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Substitute for form 1449A/B/PTO				Complete If Known	
				Application Number	10/798,753-Conf. #6431
				Filing Date	March 10, 2004
				First Named Inventor	Jack Z. Peng
				Art Unit	2827
				Examiner Name	G. N. Auduong
Sheet	1	of	2	Attorney Docket Number	384848014US

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			
	AA	US-2003/0218920-A1	11-27-2003	HARARI	
	AB	US-4,758,745	07-19-1988	EL GAMAL ET AL.	
	AC	US-4,870,302	09-26-1989	FREEMAN	
	AD	US-5,455,525	10-03-1995	HO ET AL.	
	AE	US-5,650,336	07-22-1997	ERIGUCHI ET AL.	
	AF	US-5,781,032	07-14-1998	BERTOLET ET AL.	
	AG	US-5,784,636	07-21-1998	RUPP	
	AH	US-5,889,411	03-30-1999	CHAUDHARY	
	AI	US-5,892,962	04-06-1999	CLOUTIER	
	AJ	US-5,929,482	07-27-1999	MINORU KAWAKAMI	
	AK	US-6,031,761	02-29-2000	GHILARDELLI ET AL.	
	AL	US-6,047,243	04-04-2000	DAVID BANG	
	AM	US-6,064,225	05-16-2000	ANDREWS ET AL.	
	AN	US-6,077,719	06-20-2000	NORIO KOIKE	
	AO	US-6,153,463	11-28-2000	WEI ET AL.	
	AP	US-6,198,652	03-06-2001	TAKASHI KAWAKUBO	
	AQ	US-6,236,229	05-22-2001	OR-BACH	
	AR	US-6,337,250	11-29-2001	TOMOYUKI FURUHATA	
	AS	US-6,445,619-A1	09-03-2002	MIHNEA ET AL.	
	AT	US-6,459,634	10-01-2002	JOSEPH SHER	
	AU	US-6,476,636	11-05-2002	LIEN ET AL.	
	AV	US-6,515,509	02-04-2003	BAXTER	
	AW	US-6,602,729	01-16-2003	CHUAN LIN	
	AX	US-6,633,182-A1	10-14-2003	PILEGGI ET AL.	
	AY	US-6,650,143	11-18-2003	JACK PENG	
	AZ	US-6,674,670-A1	01-06-2004	JEUNG	
	AA1	US-6,678,646	01-13-2004	MCCONNELL ET AL.	
	AB1	US-6,700,151-A1	03-02-2004	PENG	
	AC1	US-6,753,590-A1	06-22-2004	FIFIELD ET AL.	
	AD1	US-6,754,881-A1	06-22-2004	KUHLMANN ET AL.	
	AE1	US-6,777,757-A1	08-17-2004	PENG ET AL.	
	AF1	US-6,862,205-A1	03-01-2005	AGATA ET AL.	

FOREIGN PATENT DOCUMENTS					
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Examiner Signature	<i>G. N. Auduong</i>	Date Considered	7/05
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